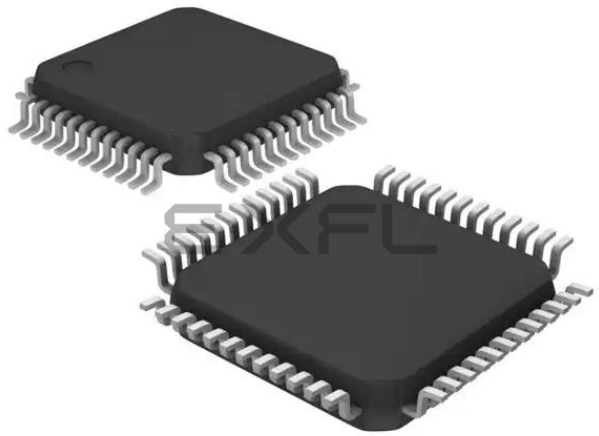

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	I²C, Microwire, SPI, SSI, SSP, UART/USART, USB
Peripherals	Brown-out Detect/Reset, POR, WDT
Number of I/O	40
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	10K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 8x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/lpc1345fbd48-151

6. Pinning information

6.1 Pinning

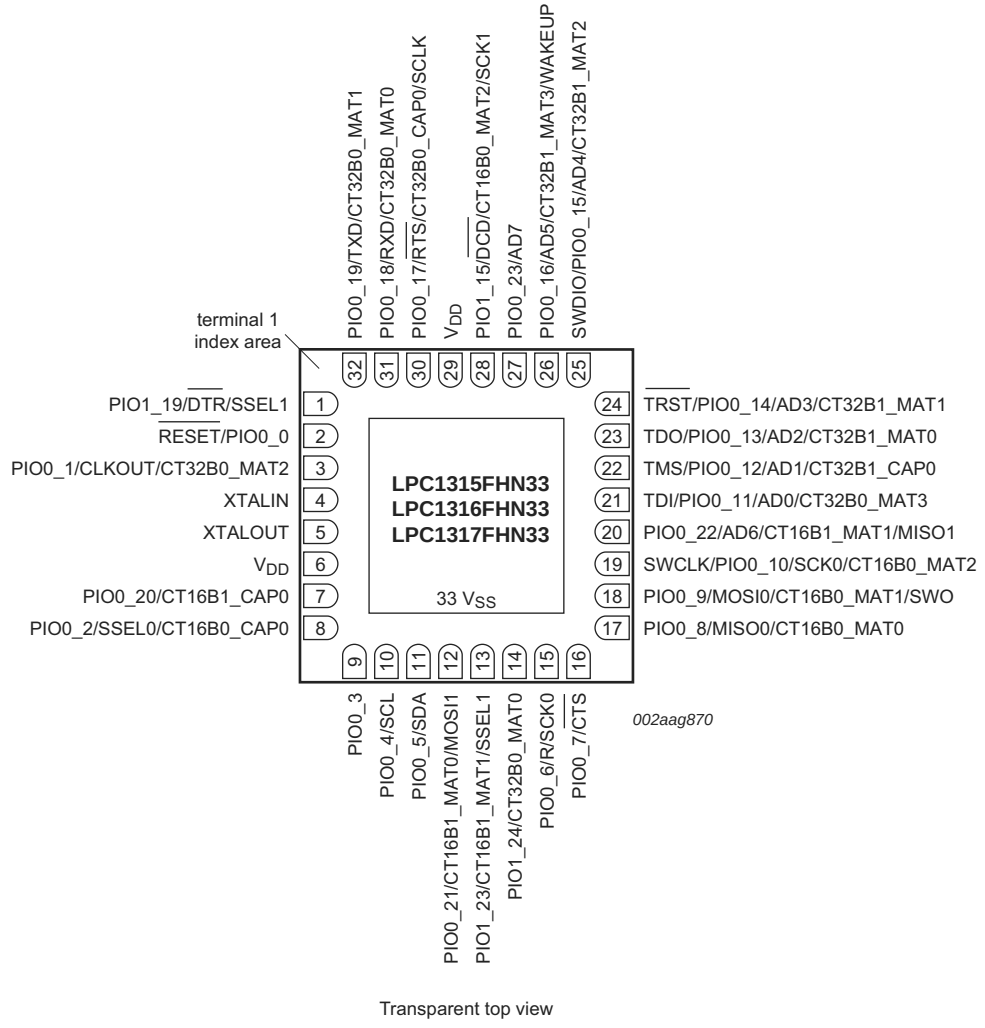


Fig 2. Pin configuration HVQFN33 package (LPC1315/16/17 - no USB)

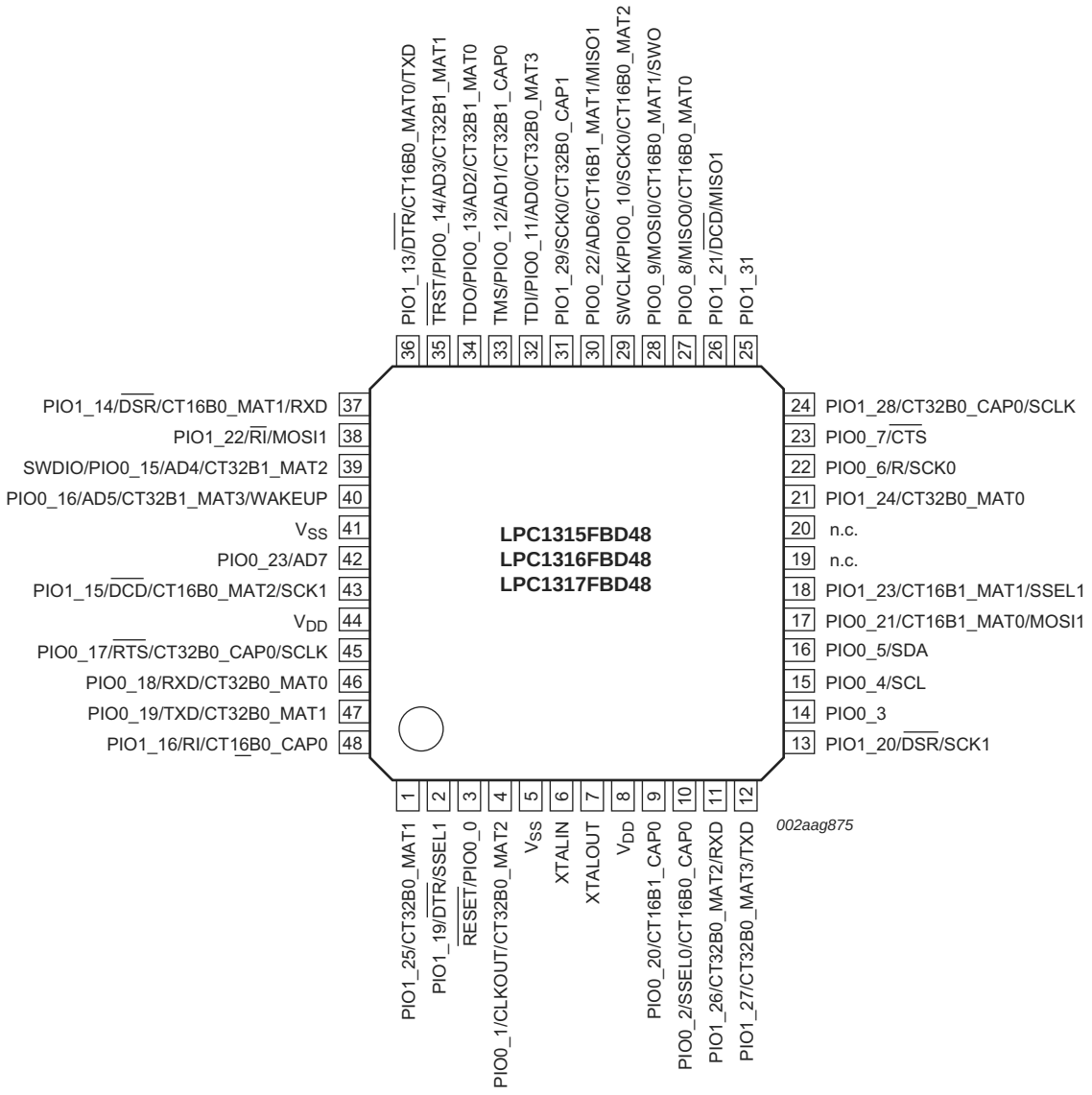
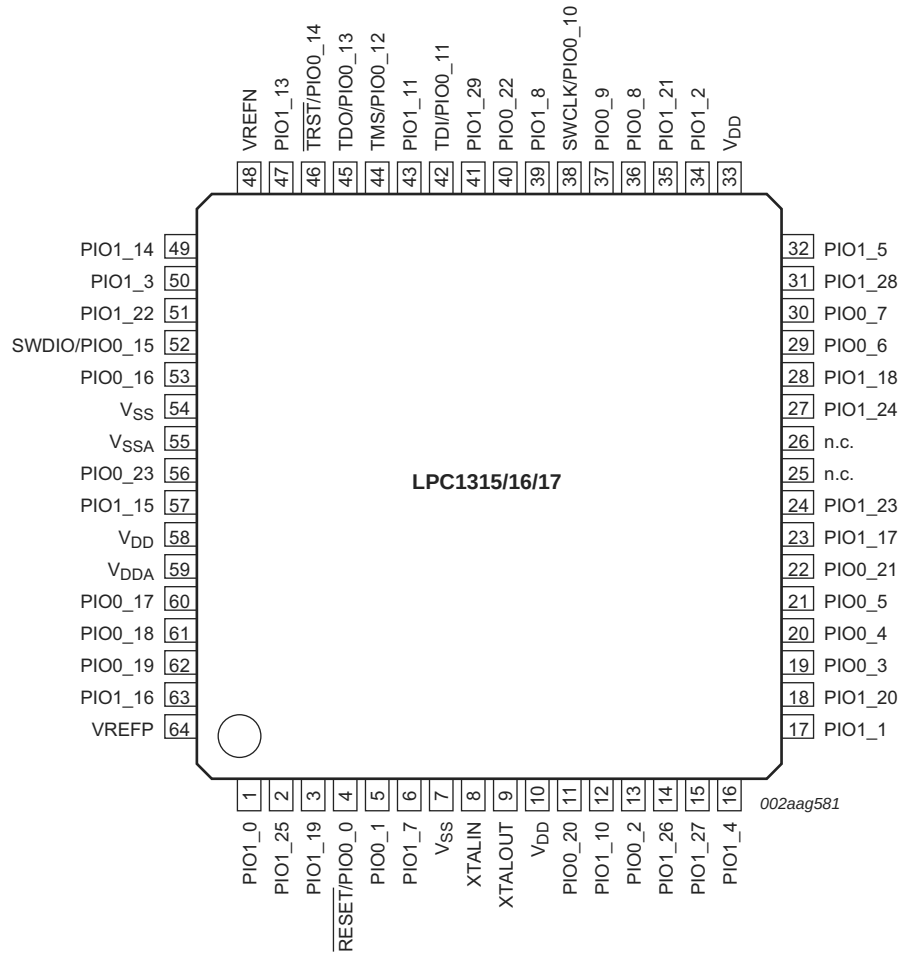


Fig 4. Pin configuration LQFP48 package (LPC1315/16/17 - no USB)



See Table 3 for the full pin name.

Fig 6. Pin configuration LQFP64 package (LPC1315/16/17 - no USB)

Table 3. Pin description (LPC1315/16/17 - no USB)

Symbol	LQFP64	LQFP48	HVQFN33	Reset state[1]	Type	Description
VREFP	64	-	-	-	-	ADC positive reference voltage: This should be nominally the same voltage as V_{DDA} but should be isolated to minimize noise and error. Level on this pin is used as a reference for ADC. This pin should be tied to 3.3 V if the ADC is not used.
V_{SSA}	55	-	-	-	-	Analog ground: 0 V reference. This should nominally be the same voltage as V_{SS}Product data sheet but should be isolated to minimize noise and error.
V_{DD}	10; 33; 58	8; 44	6; 29	-	-	Supply voltage to the internal regulator and the external rail. On LQFP48 and HVQFN33 packages, this pin is also connected to the 3.3 V ADC supply and reference voltage.
V_{SS}	7; 54	5; 41	33	-	-	Ground.

[1] Pin state at reset for default function: I = Input; O = Output; PU = internal pull-up enabled; IA = inactive, no pull-up/down enabled; F = floating; floating pins, if not used, should be tied to ground or power to minimize power consumption.

[2] See Figure 33 for the reset pad configuration. $\overline{\text{RESET}}$ functionality is not available in Deep power-down mode. Use the WAKEUP pin to reset the chip and wake up from Deep power-down mode. An external pull-up resistor is required on this pin for the Deep power-down mode.

[3] 5 V tolerant pad providing digital I/O functions with configurable pull-up/pull-down resistors and configurable hysteresis (see Figure 32).

[4] I^2C-bus pins compliant with the I^2C-bus specification for I^2C standard mode, I^2C Fast-mode, and I^2C Fast-mode Plus.

[5] 5 V tolerant pad providing digital I/O functions with configurable pull-up/pull-down resistors and configurable hysteresis (see Figure 32); includes high-current output driver.

[6] 5 V tolerant pad providing digital I/O functions with configurable pull-up/pull-down resistors, configurable hysteresis, and analog input. When configured as a ADC input, digital section of the pad is disabled and the pin is not 5 V tolerant (see Figure 32); includes programmable digital input glitch filter.

[7] WAKEUP pin. 5 V tolerant pad providing digital I/O functions with configurable pull-up/pull-down resistors, configurable hysteresis, and analog input. When configured as a ADC input, digital section of the pad is disabled and the pin is not 5 V tolerant (see Figure 32); includes digital input glitch filter.

[8] When the system oscillator is not used, connect XTALIN and XTALOUT as follows: XTALIN can be left floating or can be grounded (grounding is preferred to reduce susceptibility to noise). XTALOUT should be left floating.

Table 4. Pin description (LPC1345/46/47 - with USB)

Symbol	LQFP64	LQFP48	HVQFN33		Reset state[1]	Type	Description
$\overline{\text{RESET}}$/PIO0_0	4	3	2	[2]	I; PU	I	**$\overline{\text{RESET}}$ —** External reset input with 20 ns glitch filter. A LOW-going pulse as short as 50 ns on this pin resets the device, causing I/O ports and peripherals to take on their default states, and processor execution to begin at address 0. This pin also serves as the debug select input. LOW level selects the JTAG boundary scan. HIGH level selects the ARM SWD debug mode.
					-	I/O	**PIO0_0 —** General purpose digital input/output pin.
PIO0_1/CLKOUT/ CT32B0_MAT2/ USB_FTOGGLE	5	4	3	[3]	I; PU	I/O	**PIO0_1 —** General purpose digital input/output pin. A LOW level on this pin during reset starts the ISP command handler or the USB device enumeration.
					-	O	**CLKOUT —** Clockout pin.
					-	O	**CT32B0_MAT2 —** Match output 2 for 32-bit timer 0.
					-	O	**USB_FTOGGLE —** USB 1 ms Start-of-Frame signal.
PIO0_2/SSEL0/ CT16B0_CAP0	13	10	8	[3]	I; PU	I/O	**PIO0_2 —** General purpose digital input/output pin.
						I/O	**SSEL0 —** Slave select for SSP0.
						I	**CT16B0_CAP0 —** Capture input 0 for 16-bit timer 0.
PIO0_3/USB_VBUS	19	14	9	[3]	I; PU	I/O	**PIO0_3 —** General purpose digital input/output pin. A LOW level on this pin during reset starts the ISP command handler. A HIGH level during reset starts the USB device enumeration.
					-	I	**USB_VBUS —** Monitors the presence of USB bus power.
PIO0_4/SCL	20	15	10	[4]	IA	I/O	**PIO0_4 —** General purpose digital input/output pin (open-drain).
					-	I/O	**SCL —** I^2C-bus clock input/output (open-drain). High-current sink only if I^2C Fast-mode Plus is selected in the I/O configuration register.
PIO0_5/SDA	21	16	11	[4]	IA	I/O	**PIO0_5 —** General purpose digital input/output pin (open-drain).
					-	I/O	**SDA —** I^2C-bus data input/output (open-drain). High-current sink only if I^2C Fast-mode Plus is selected in the I/O configuration register.
PIO0_6/$\overline{\text{USB_CONNECT}}$/ SCK0	29	22	15	[3]	I; PU	I/O	**PIO0_6 —** General purpose digital input/output pin.
					-	O	**$\overline{\text{USB_CONNECT}}$ —** Signal used to switch an external 1.5 kΩ resistor under software control. Used with the SoftConnect USB feature.
					-	I/O	**SCK0 —** Serial clock for SSP0.
PIO0_7/$\overline{\text{CTS}}$	30	23	16	[5]	I; PU	I/O	**PIO0_7 —** General purpose digital input/output pin (high-current output driver).
					-	I	**$\overline{\text{CTS}}$ —** Clear To Send input for USART.
PIO0_8/MISO0/ CT16B0_MAT0	36	27	17	[3]	I; PU	I/O	**PIO0_8 —** General purpose digital input/output pin.
					-	I/O	**MISO0 —** Master In Slave Out for SSP0.
					-	O	**CT16B0_MAT0 —** Match output 0 for 16-bit timer 0.

7.14.1 Features

- A 32-bit/16-bit timer/counter with a programmable 32-bit/16-bit prescaler.
- Counter or timer operation.
- One capture channel per timer, that can take a snapshot of the timer value when an input signal transitions. A capture event may also generate an interrupt.
- Four match registers per timer that allow:
  - Continuous operation with optional interrupt generation on match.
  - Stop timer on match with optional interrupt generation.
  - Reset timer on match with optional interrupt generation.
- Up to four external outputs corresponding to match registers, with the following capabilities:
  - Set LOW on match.
  - Set HIGH on match.
  - Toggle on match.
  - Do nothing on match.
- The timer and prescaler may be configured to be cleared on a designated capture event. This feature permits easy pulse-width measurement by clearing the timer on the leading edge of an input pulse and capturing the timer value on the trailing edge.

7.15 Repetitive Interrupt (RI) timer

The repetitive interrupt timer provides a free-running 48-bit counter which is compared to a selectable value, generating an interrupt when a match occurs. Any bits of the timer/compare can be masked such that they do not contribute to the match detection. The repetitive interrupt timer can be used to create an interrupt that repeats at predetermined intervals.

7.15.1 Features

- 48-bit counter running from the main clock. Counter can be free-running or can be reset when an RIT interrupt is generated.
- 48-bit compare value.
- 48-bit compare mask. An interrupt is generated when the counter value equals the compare value, after masking. This allows for combinations not possible with a simple compare.
- Support for ETM timestamp generator.

7.16 System tick timer

The ARM Cortex-M3 includes a system tick timer (SYSTICK) that is intended to generate a dedicated SYSTICK exception at a fixed time interval (typically 10 ms).

7.17 Windowed WatchDog Timer (WWDT)

The purpose of the watchdog is to reset the controller if software fails to periodically service it within a programmable time window.

7.18.6.3 Code security (Code Read Protection - CRP)

This feature of the LPC1315/16/17/45/46/47 allows user to enable different levels of security in the system so that access to the on-chip flash and use of the Serial Wire Debugger (SWD) and In-System Programming (ISP) can be restricted. When needed, CRP is invoked by programming a specific pattern into a dedicated flash location. IAP commands are not affected by the CRP.

In addition, ISP entry via the PIO0_1 pin can be disabled without enabling CRP. For details see the LPC1315/16/17/45/46/47 *user manual*.

There are three levels of Code Read Protection:

1. CRP1 disables access to the chip via the SWD and allows partial flash update (excluding flash sector 0) using a limited set of the ISP commands. This mode is useful when CRP is required and flash field updates are needed but all sectors can not be erased.
2. CRP2 disables access to the chip via the SWD and only allows full flash erase and update using a reduced set of the ISP commands.
3. Running an application with level CRP3 selected fully disables any access to the chip via the SWD pins and the ISP. This mode effectively disables ISP override using PIO0_1 pin, too. It is up to the user's application to provide (if needed) flash update mechanism using IAP calls or call reinvoke ISP command to enable flash update via the USART.

CAUTION

If level three Code Read Protection (CRP3) is selected, no future factory testing can be performed on the device.

In addition to the three CRP levels, sampling of pin PIO0_1 for valid user code can be disabled. For details see the LPC1315/16/17/45/46/47 *user manual*.

7.18.6.4 APB interface

The APB peripherals are located on one APB bus.

7.18.6.5 AHBLite

The AHBLite connects the CPU bus of the ARM Cortex-M3 to the flash memory, the main static RAM, and the ROM.

7.18.6.6 External interrupt inputs

All GPIO pins can be level or edge sensitive interrupt inputs.

7.19 Emulation and debugging

Debug functions are integrated into the ARM Cortex-M3. Serial wire debug functions are supported in addition to a standard JTAG boundary scan. The ARM Cortex-M0 is configured to support up to four breakpoints and two watch points.

9. Static characteristics

Table 6. Static characteristics

T_{amb} = −40 °C to +85 °C, unless otherwise specified.

Symbol	Parameter	Conditions		Min	Typ[1]	Max	Unit
V_{DD}	supply voltage (core and external rail)		[2]	2.0	3.3	3.6	V
I_{DD}	supply current	Active mode; V_{DD} = 3.3 V; T_{amb} = 25 °C; code `while(1){}` executed from flash;					
		system clock = 1 MHz	[3][5][6][7][8][9]	-	0.5	-	mA
		system clock = 12 MHz	[4][5][6][7][8][9]	-	2	-	mA
		system clock = 72 MHz	[5][6][7][8][9][10]	-	14	-	mA
		Sleep mode; V_{DD} = 3.3 V; T_{amb} = 25 °C; system clock = 12 MHz	[4][5][6][7][8][9]	-	1	-	mA
		Deep-sleep mode; V_{DD} = 3.3 V; T_{amb} = 25 °C	[5][8]	-	280	-	μA
		Power-down mode; V_{DD} = 3.3 V; T_{amb} = 25 °C	[5][8]	-	2.1	-	μA
		Deep power-down mode; V_{DD} = 3.3 V; T_{amb} = 25 °C	[11]	-	220	-	nA
Standard port pins, $\overline{\text{RESET}}$							
I_{IL}	LOW-level input current	V_I = 0 V; on-chip pull-up resistor disabled		-	0.5	10	nA
I_{IH}	HIGH-level input current	V_I = V_{DD}; on-chip pull-down resistor disabled		-	0.5	10	nA
I_{OZ}	OFF-state output current	V_O = 0 V; V_O = V_{DD}; on-chip pull-up/down resistors disabled		-	0.5	10	nA
V_I	input voltage	pin configured to provide a digital function	[12][13][14]	0	-	5.0	V
V_O	output voltage	output active		0	-	V_{DD}	V
V_{IH}	HIGH-level input voltage			$0.7V_{DD}$	-	-	V
V_{IL}	LOW-level input voltage			-	-	$0.3V_{DD}$	V
V_{hys}	hysteresis voltage			-	0.4	-	V
V_{OH}	HIGH-level output voltage	2.5 V< V_{DD} ≤ 3.6 V; I_{OH} = −4 mA		V_{DD} − 0.4	-	-	V
		2.0 V ≤ V_{DD} < 2.5 V; I_{OH} = −3 mA		V_{DD} − 0.4	-	-	V
V_{OL}	LOW-level output voltage	2.5 V ≤ V_{DD} ≤ 3.6 V; I_{OL} = 4 mA		-	-	0.4	V
		2.0 V ≤ V_{DD} < 2.5 V; I_{OL} = 3 mA		-	-	0.4	V

[3] System oscillator enabled; PLL and IRC disabled.

[4] IRC enabled; system oscillator disabled; system PLL disabled.

[5] I_{DD} measurements were performed with all pins configured as GPIO outputs driven LOW and pull-up resistors disabled.

[6] BOD disabled.

[7] All peripherals disabled in the AHBCLKCTRL register. Peripheral clocks to USART, SSP0/1 disabled in the syscon block.

[8] USB_DP and USB_DM pulled LOW externally.

[9] Low-current mode PWR_LOW_CURRENT selected when running the set_power routine in the power profiles.

[10] IRC disabled; system oscillator enabled; system PLL enabled.

[11] WAKEUP pin pulled HIGH externally. An external pull-up resistor is required on the $\overline{\text{RESET}}$ pin for the Deep power-down mode.

[12] Including voltage on outputs in 3-state mode.

[13] V_{DD} supply voltage must be present.

[14] 3-state outputs go into 3-state mode in Deep power-down mode.

[15] Allowed as long as the current limit does not exceed the maximum current allowed by the device.

[16] To V_{SS}.

[17] Includes external resistors of 33 Ω ± 1 % on USB_DP and USB_DM.

9.1 BOD static characteristics

Table 7. BOD static characteristics[1]

T_{amb} = 25 °C.

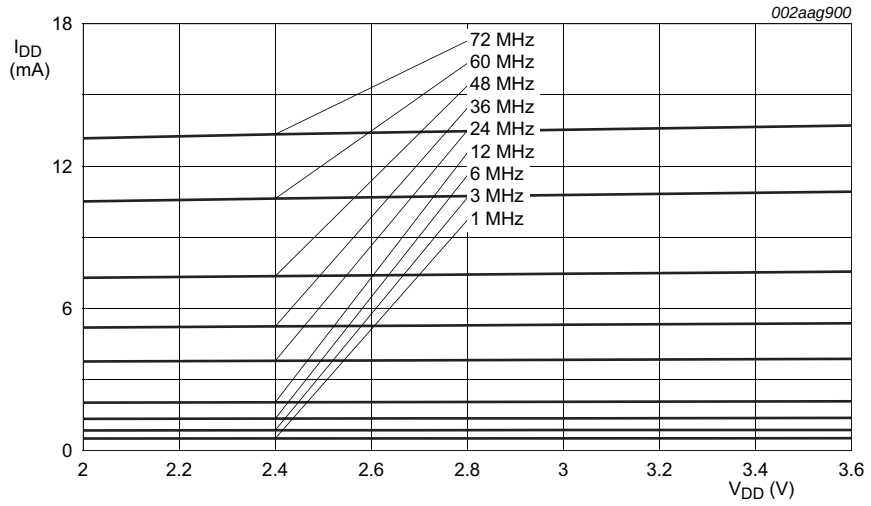
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{th}	threshold voltage	interrupt level 1				
		assertion	-	2.22	-	V
		de-assertion	-	2.35	-	V
		interrupt level 2				
		assertion	-	2.52	-	V
		de-assertion	-	2.66	-	V
		interrupt level 3				
		assertion	-	2.80	-	V
		de-assertion	-	2.90	-	V
		reset level 0				
		assertion	-	1.46	-	V
		de-assertion	-	1.63	-	V
		reset level 1				
		assertion	-	2.06	-	V
		de-assertion	-	2.15	-	V
		reset level 2				
		assertion	-	2.35	-	V
		de-assertion	-	2.43	-	V
		reset level 3				
		assertion	-	2.63	-	V
		de-assertion	-	2.71	-	V

[1] Interrupt levels are selected by writing the level value to the BOD control register BODCTRL, see LPC1315/16/17/45/46/47 *user manual*.

9.2 Power consumption

Power measurements in Active, Sleep, and Deep-sleep modes were performed under the following conditions (see LPC1315/16/17/45/46/47 *user manual*):

- Configure all pins as GPIO with pull-up resistor disabled in the IOCON block.
- Configure GPIO pins as outputs using the GPIOnDIR registers.
- Write 0 to all GPIOnDATA registers to drive the outputs LOW.



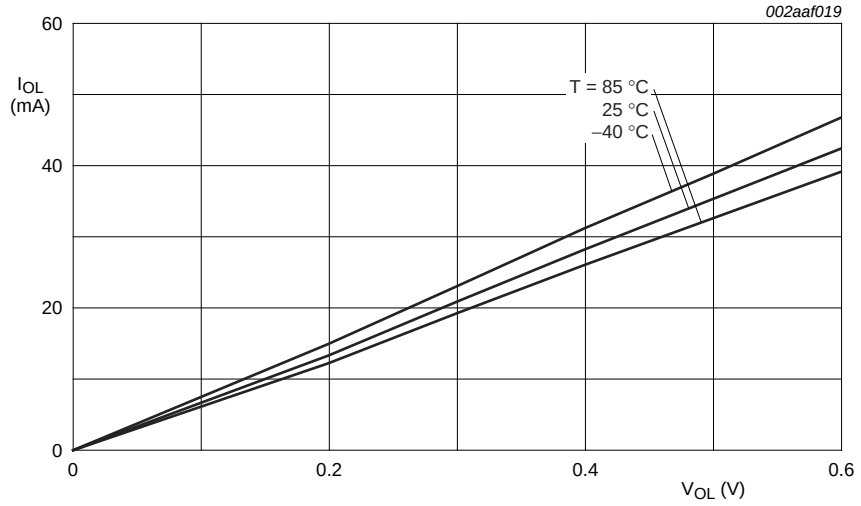
Conditions: T_{amb} = 25 °C; active mode entered executing code `while(1){}` from flash; internal pull-up resistors disabled; BOD disabled; all peripherals disabled in the SYSAHBCLKCTRL register; all peripheral clocks disabled; USB_DP and USB_DM pulled LOW externally.

1 MHz - 6 MHz: system oscillator enabled; PLL, IRC disabled.

12 MHz: IRC enabled; system oscillator, PLL disabled.

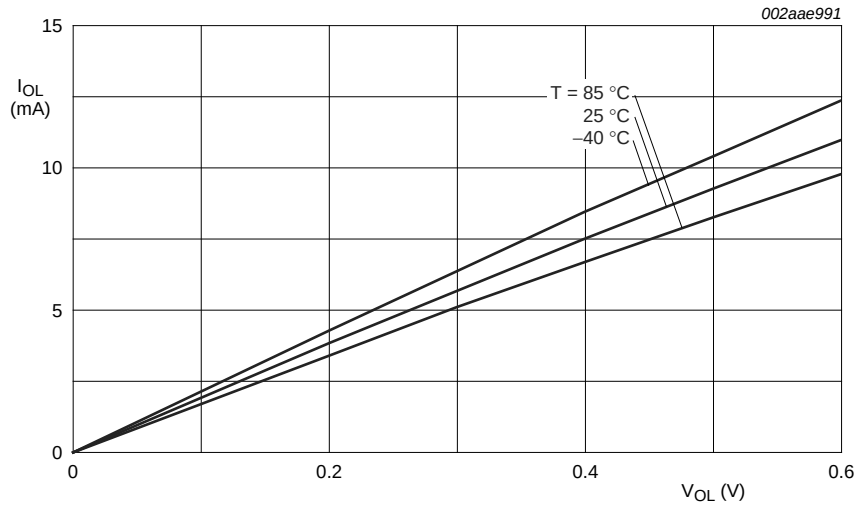
24 MHz - 72 MHz: IRC disabled; system oscillator, PLL enabled.

Fig 10. Typical supply current versus regulator supply voltage V_{DD} in active mode



Conditions: V_{DD} = 3.3 V; on pins PIO0_4 and PIO0_5.

Fig 17. I^2C-bus pins (high current sink): Typical LOW-level output current I_{OL} versus LOW-level output voltage V_{OL}



Conditions: V_{DD} = 3.3 V; standard port pins and PIO0_7.

Fig 18. Typical LOW-level output current I_{OL} versus LOW-level output voltage V_{OL}

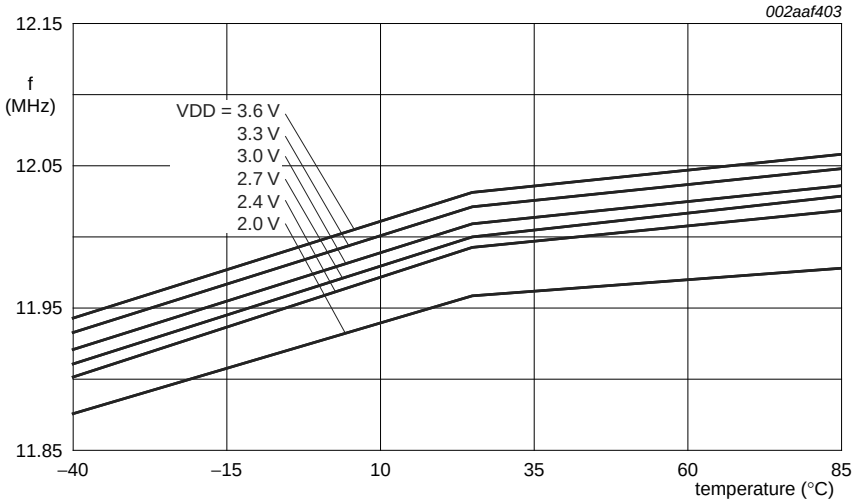
10.3 Internal oscillators

Table 12. Dynamic characteristics: IRC
T_{amb} = −40 °C to +85 °C; 2.7 V ≤ V_{DD} ≤ 3.6 V[1].

Symbol	Parameter	Conditions	Min	Typ[2]	Max	Unit
$f_{osc(RC)}$	internal RC oscillator frequency	-	11.88	12	12.12	MHz

[1] Parameters are valid over operating temperature range unless otherwise specified.

[2] Typical ratings are not guaranteed. The values listed are at room temperature (25 °C), nominal supply voltages.



Conditions: Frequency values are typical values. 12 MHz ± 1 % accuracy is guaranteed for 2.7 V ≤ V_{DD} ≤ 3.6 V and T_{amb} = −40 °C to +85 °C. Variations between parts may cause the IRC to fall outside the 12 MHz ± 1 % accuracy specification for voltages below 2.7 V.

Fig 23. Internal RC oscillator frequency versus temperature

Table 13. Dynamic characteristics: Watchdog oscillator

Symbol	Parameter	Conditions		Min	Typ[1]	Max	Unit
$f_{osc(int)}$	internal oscillator frequency	DIVSEL = 0x1F, FREQSEL = 0x1 in the WDTOSCCTRL register;	[2][3]	-	9.4	-	kHz
		DIVSEL = 0x00, FREQSEL = 0xF in the WDTOSCCTRL register	[2][3]	-	2300	-	kHz

[1] Typical ratings are not guaranteed. The values listed are at nominal supply voltages.

[2] The typical frequency spread over processing and temperature (T_{amb} = −40 °C to +85 °C) is ±40 %.

[3] See the LPC1315/16/17/45/46/47 *user manual.*

10.4 I/O pins

Table 14. Dynamic characteristics: I/O pins[1]
T_{amb} = −40 °C to +85 °C; 3.0 V ≤ V_{DD} ≤ 3.6 V.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
t_r	rise time	pin configured as output	3.0	-	5.0	ns
t_f	fall time	pin configured as output	2.5	-	5.0	ns

[1] Applies to standard port pins and $\overline{\text{RESET}}$ pin.

10.5 I²C-bus

Table 15. Dynamic characteristic: I²C-bus pins[1]
T_{amb} = −40 °C to +85 °C.[2]

Symbol	Parameter		Conditions	Min	Max	Unit
f_{SCL}	SCL clock frequency		Standard-mode	0	100	kHz
			Fast-mode	0	400	kHz
			Fast-mode Plus	0	1	MHz
t_f	fall time	[4][5][6][7]	of both SDA and SCL signals	-	300	ns
			Standard-mode			
			Fast-mode	20 + 0.1 × C_b	300	ns
			Fast-mode Plus	-	120	ns
t_{LOW}	LOW period of the SCL clock		Standard-mode	4.7	-	µs
			Fast-mode	1.3	-	µs
			Fast-mode Plus	0.5	-	µs
t_{HIGH}	HIGH period of the SCL clock		Standard-mode	4.0	-	µs
			Fast-mode	0.6	-	µs
			Fast-mode Plus	0.26	-	µs
$t_{HD;DAT}$	data hold time	[3][4][8]	Standard-mode	0	-	µs
			Fast-mode	0	-	µs
			Fast-mode Plus	0	-	µs
$t_{SU;DAT}$	data set-up time	[9][10]	Standard-mode	250	-	ns
			Fast-mode	100	-	ns
			Fast-mode Plus	50	-	ns

[1] See the I²C-bus specification *UM10204* for details.

[2] Parameters are valid over operating temperature range unless otherwise specified.

[3] tHD;DAT is the data hold time that is measured from the falling edge of SCL; applies to data in transmission and the acknowledge.

[4] A device must internally provide a hold time of at least 300 ns for the SDA signal (with respect to the V_{IH}(min) of the SCL signal) to bridge the undefined region of the falling edge of SCL.

[5] C_b = total capacitance of one bus line in pF.

[6] The maximum t_f for the SDA and SCL bus lines is specified at 300 ns. The maximum fall time for the SDA output stage t_f is specified at 250 ns. This allows series protection resistors to be connected in between the SDA and the SCL pins and the SDA/SCL bus lines without exceeding the maximum specified t_f.

[7] In Fast-mode Plus, fall time is specified the same for both output stage and bus timing. If series resistors are used, designers should allow for this when considering bus timing.

10.6 SSP interface

Table 16. Dynamic characteristics: SSP pins in SPI mode

Symbol	Parameter	Conditions		Min	Max	Unit
SSP master						
$T_{cy(clk)}$	clock cycle time	full-duplex mode	[1]	40	-	ns
		when only transmitting	[1]	27.8	-	ns
t_{DS}	data set-up time	in SPI mode; $2.4\ V \leq V_{DD} \leq 3.6\ V$	[2]	15	-	ns
		$2.0\ V \leq V_{DD} < 2.4\ V$	[2]	20	-	ns
t_{DH}	data hold time	in SPI mode	[2]	0	-	ns
$t_{v(Q)}$	data output valid time	in SPI mode	[2]	-	10	ns
$t_{h(Q)}$	data output hold time	in SPI mode	[2]	0	-	ns
SSP slave						
$T_{cy(PCLK)}$	PCLK cycle time			13.9	-	ns
t_{DS}	data set-up time	in SPI mode	[3][4]	0	-	ns
t_{DH}	data hold time	in SPI mode	[3][4]	$3 \times T_{cy(PCLK)} + 4$	-	ns
$t_{v(Q)}$	data output valid time	in SPI mode	[3][4]	-	$3 \times T_{cy(PCLK)} + 11$	ns
$t_{h(Q)}$	data output hold time	in SPI mode	[3][4]	-	$2 \times T_{cy(PCLK)} + 5$	ns

[1] $T_{cy(clk)} = (SSPCLKDIV \times (1 + SCR) \times CPSDVSR) / f_{main}$. The clock cycle time derived from the SPI bit rate $T_{cy(clk)}$ is a function of the main clock frequency f_{main}, the SSP peripheral clock divider (SSPCLKDIV), the SSP SCR parameter (specified in the SSP0CR0 register), and the SSP CPSDVSR parameter (specified in the SSP clock prescale register).

[2] $T_{amb} = -40\ °C$ to $85\ °C$.

[3] $T_{cy(clk)} = 12 \times T_{cy(PCLK)}$.

[4] $T_{amb} = 25\ °C$; $V_{DD} = 3.3\ V$.

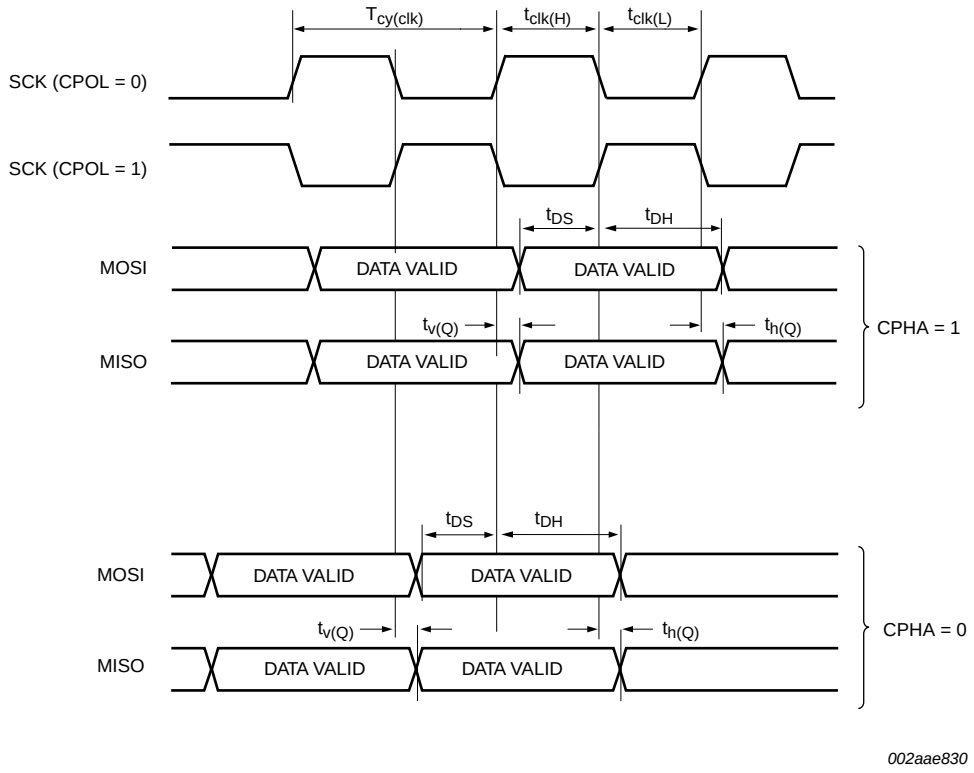
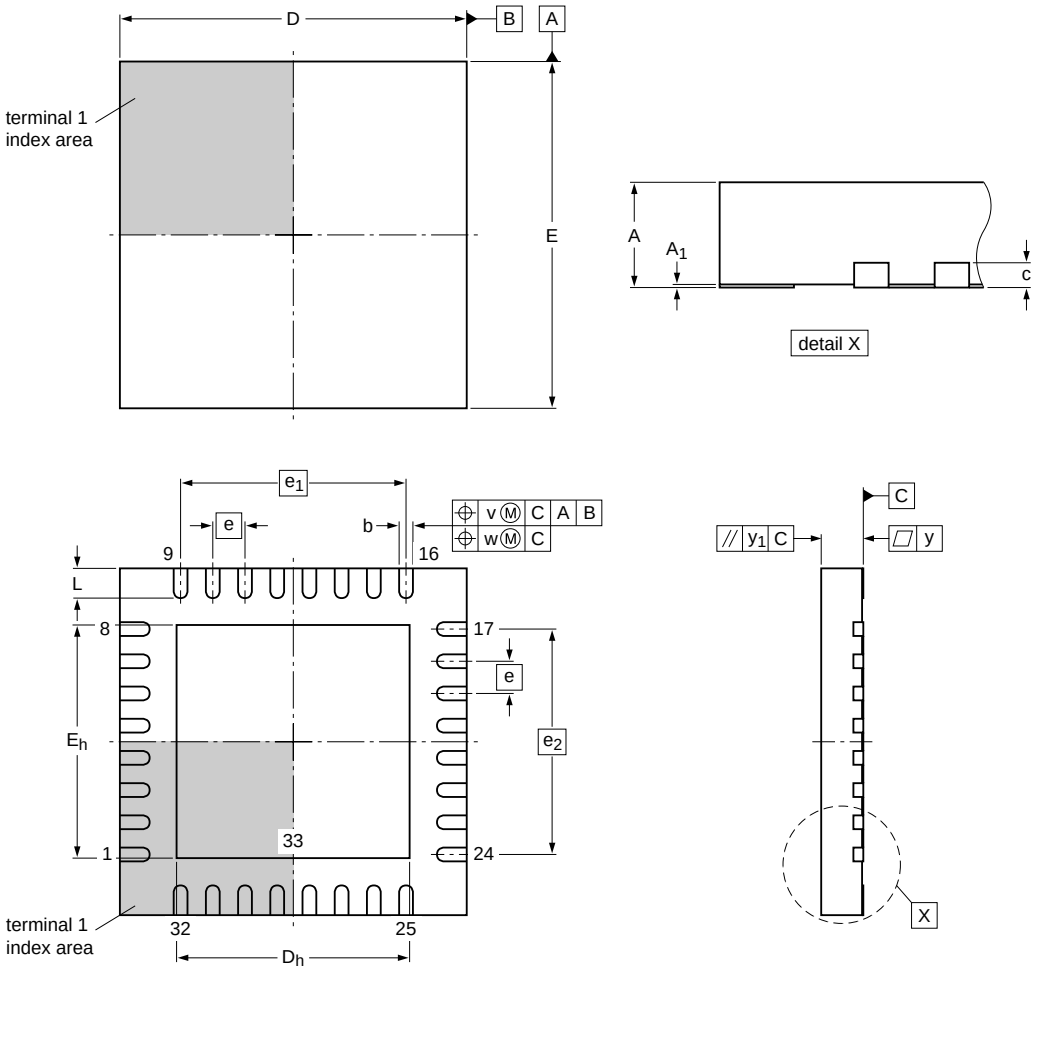


Fig 26. SSP slave timing in SPI mode

13. Package outline

HVQFN33: plastic thermal enhanced very thin quad flat package; no leads; 33 terminals; body 7 x 7 x 0.85 mm



Dimensions

Unit		$A^{(1)}$	A_1	b	c	$D^{(1)}$	D_h	$E^{(1)}$	E_h	e	e_1	e_2	L	v	w	y	y_1
	max	1.00	0.05	0.35		7.1	4.85	7.1	4.85				0.75				
mm	nom	0.85	0.02	0.28	0.2	7.0	4.70	7.0	4.70	0.65	4.55	4.55	0.60	0.1	0.05	0.08	0.1
	min	0.80	0.00	0.23		6.9	4.55	6.9	4.55				0.45				

Note

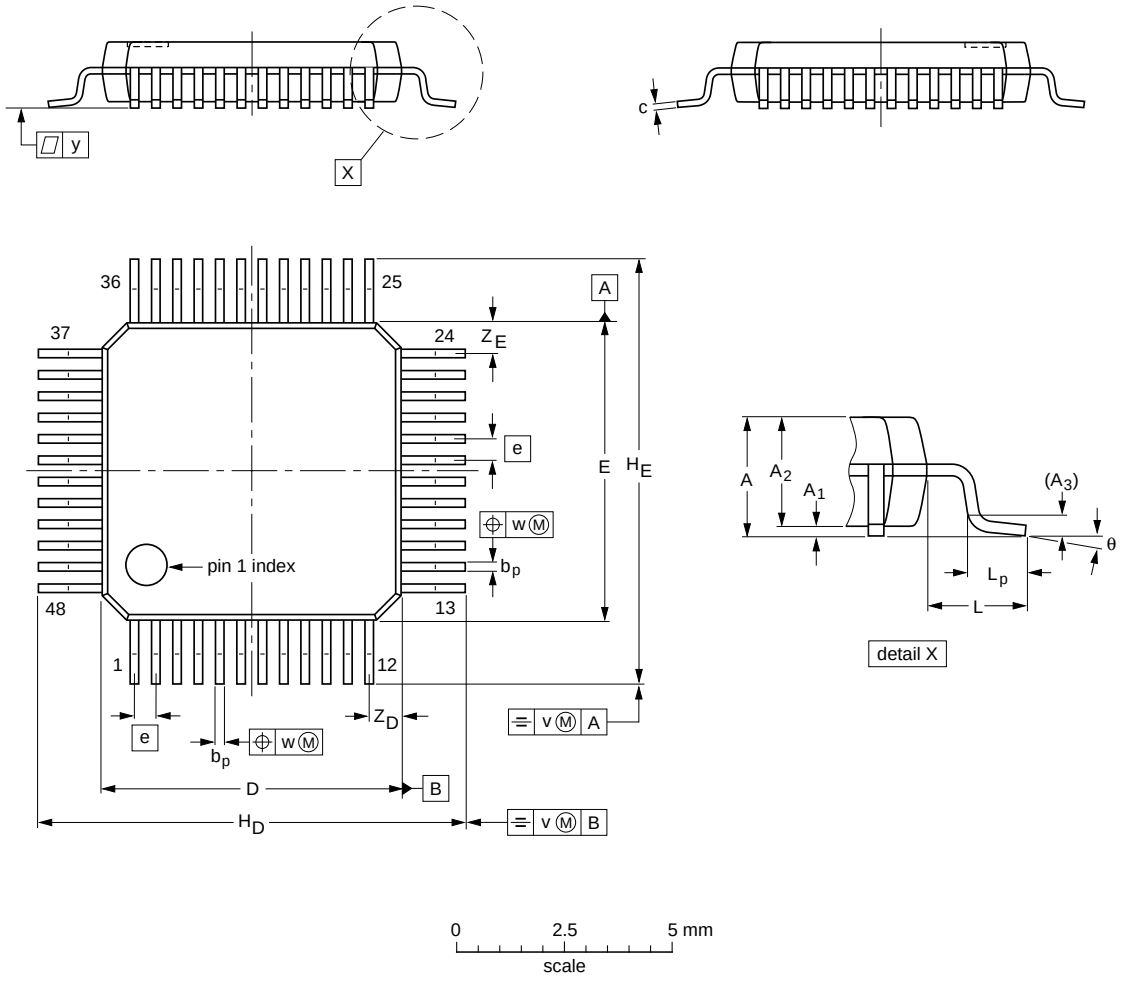
1. Plastic or metal protrusions of 0.075 mm maximum per side are not included.

hvqfn33_po

Outline version	References				European projection	Issue date
	IEC	JEDEC	JEITA			
		- - -				~~09-03-17~~ 09-03-23

Fig 34. Package outline HVQFN33

LQFP48: plastic low profile quad flat package; 48 leads; body 7 x 7 x 1.4 mm **SOT313-2**



DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A_1	A_2	A_3	b_p	c	$D^{(1)}$	$E^{(1)}$	e	H_D	H_E	L	L_p	v	w	y	$Z_D^{(1)}$	$Z_E^{(1)}$	θ
mm	1.6	0.20 0.05	1.45 1.35	0.25	0.27 0.17	0.18 0.12	7.1 6.9	7.1 6.9	0.5	9.15 8.85	9.15 8.85	1	0.75 0.45	0.2	0.12	0.1	0.95 0.55	0.95 0.55	7^o 0^o

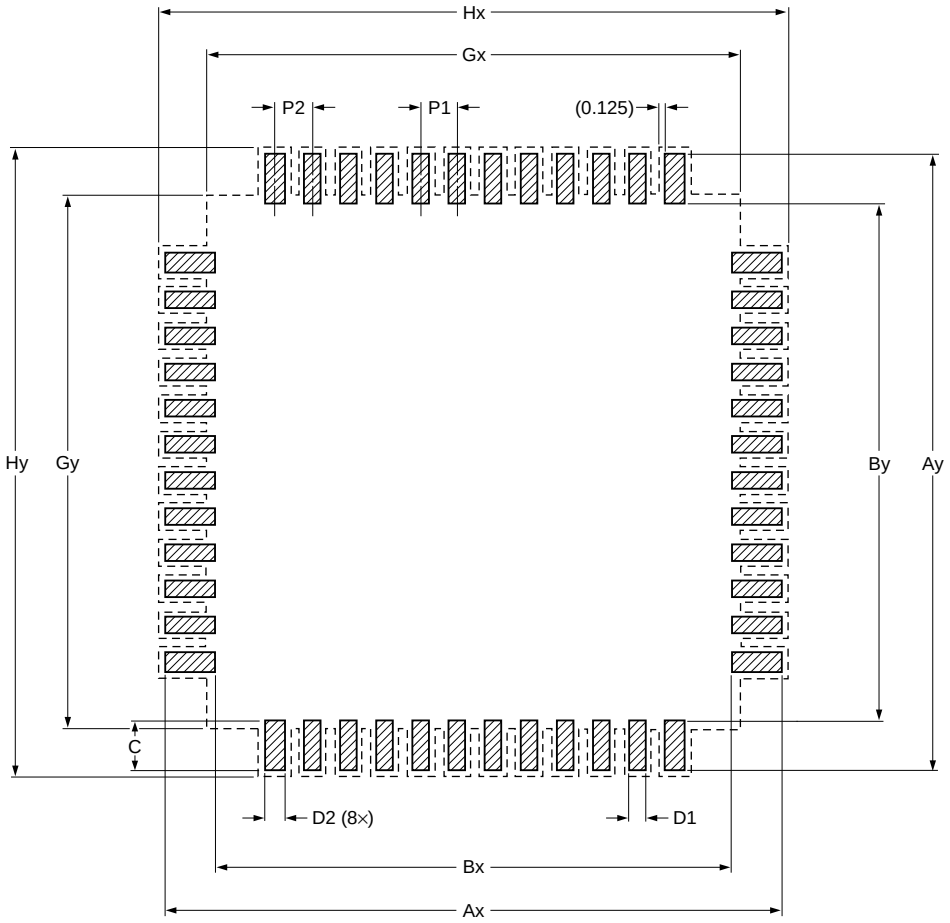
Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT313-2	136E05	MS-026				~~00-01-19~~ 03-02-25

Fig 35. Package outline LQFP48 (SOT313-2)

Footprint information for reflow soldering of LQFP48 package **SOT313-2**



Generic footprint pattern

Refer to the package outline drawing for actual layout

solder land

occupied area

DIMENSIONS in mm

P1	P2	Ax	Ay	Bx	By	C	D1	D2	Gx	Gy	Hx	Hy
0.500	0.560	10.350	10.350	7.350	7.350	1.500	0.280	0.500	7.500	7.500	10.650	10.650

sot313-2_fr

Fig 38. Reflow soldering of the LQFP48 package

17. Legal information

17.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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